

U-TRR

Uncovering in-DRAM RowHammer Protection Mechanisms:
A New Methodology, Custom RowHammer Patterns, and Implications

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Summary

DRAM **RowHammer** vulnerability leads to critical reliability and security issues

Target Row Refresh (TRR):

a set of **obscure**, **undocumented**, and **proprietary** RowHammer mitigation techniques

Is TRR fully secure? How can we validate its security guarantees?

U-TRR

A new methodology that leverages *data retention failures* to uncover the inner workings of TRR and study its security

High-Level Operation

- 1) Profile the retention time of a row R
- 2) Find when TRR refreshes R to understand the underlying TRR mechanism

15x Vendor A
DDR4 modules



15x Vendor B
DDR4 modules



15x Vendor C
DDR4 modules



U-TRR



New

RowHammer
access patterns



All 45 modules we test are **vulnerable**

99.9% of rows in a DRAM bank
experience **at least one RowHammer bit flip**

Up to 7 RowHammer **bit flips** in
an 8-byte dataword, **making ECC ineffective**

U-TRR can enable **more secure** RowHammer solutions

Outline

1. DRAM Operation Basics

2. RowHammer & Target Row Refresh

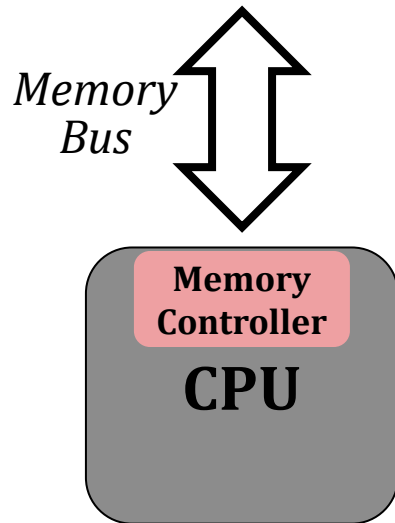
3. The U-TRR Methodology

4. Observations & New RowHammer Access Patterns

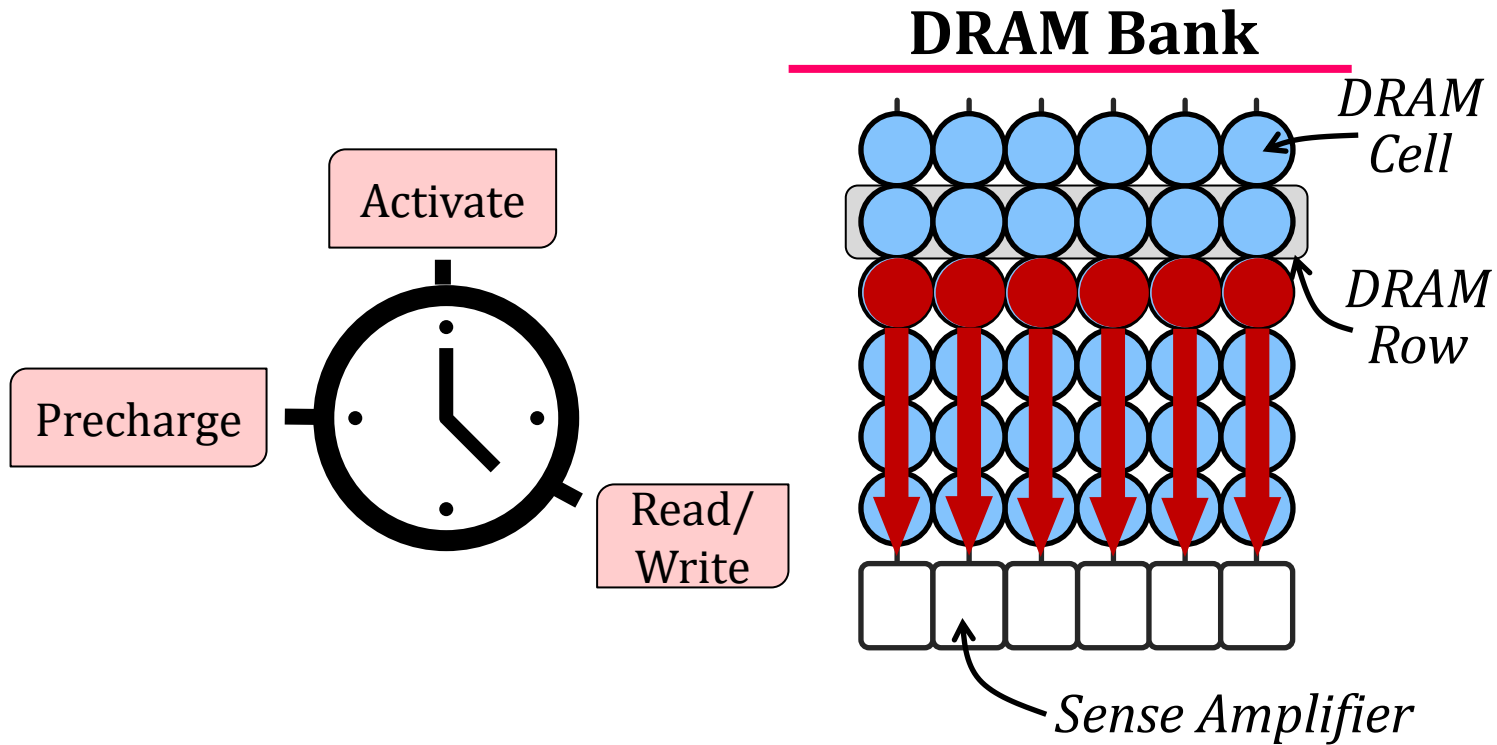
5. RowHammer Bit Flip Analysis

6. Takeaways and Conclusion

DRAM Organization

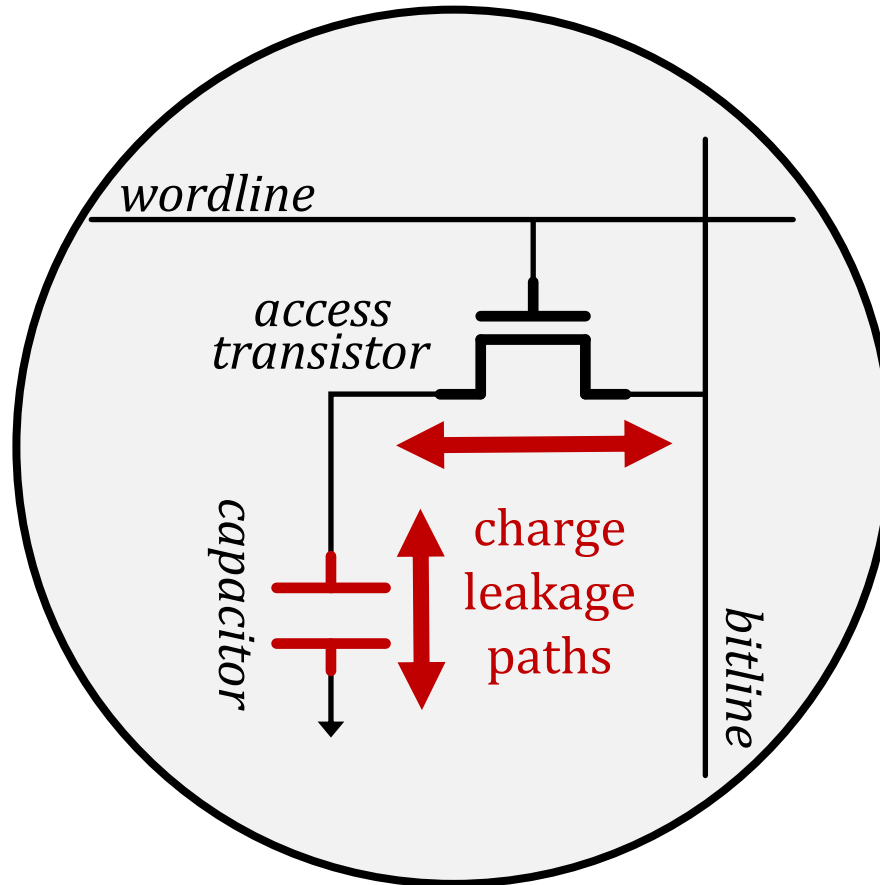


Accessing DRAM



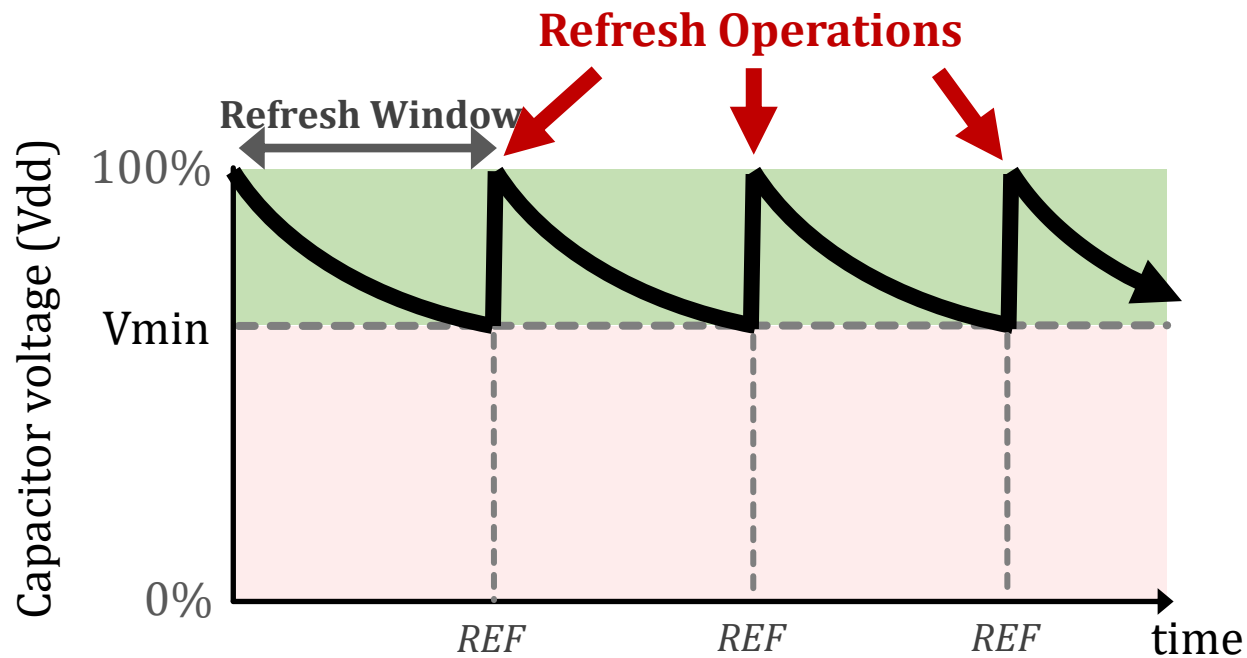
DRAM Cell Leakage

Each cell encodes information in **leaky** capacitors



Stored data is **corrupted** if too much charge leaks (i.e., the capacitor voltage degrades too much)

DRAM Refresh



Periodic **refresh operations** preserve stored data

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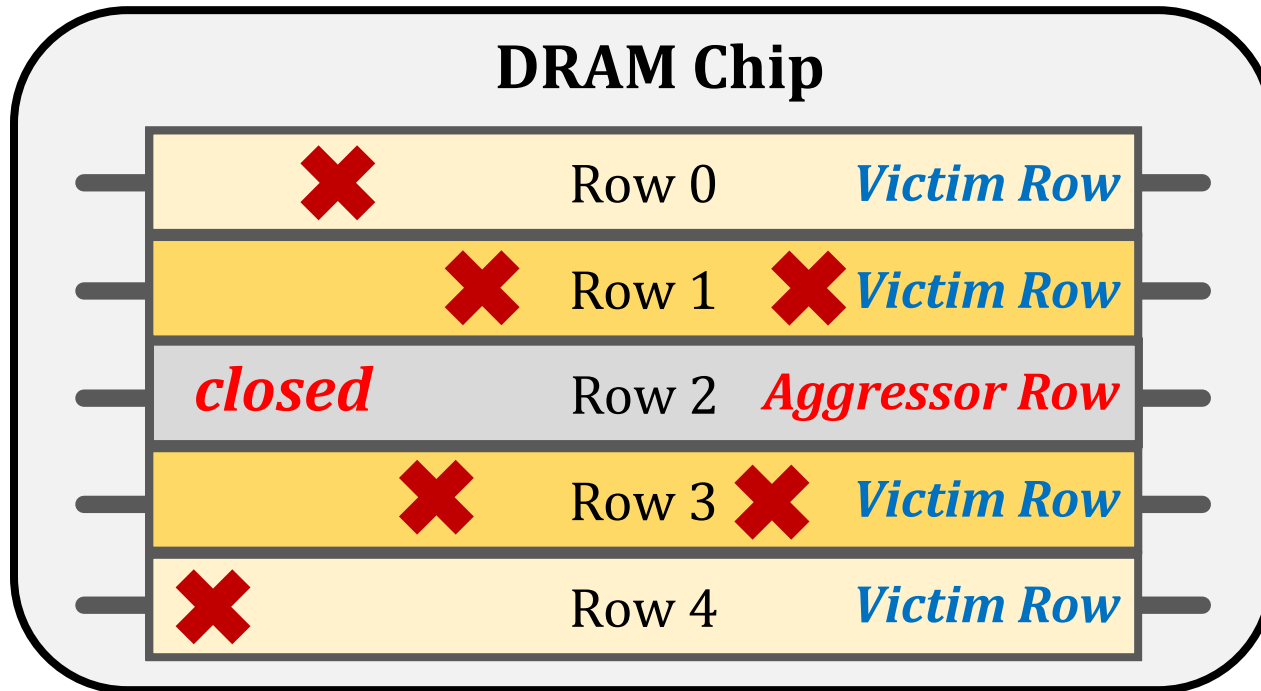
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The RowHammer Vulnerability

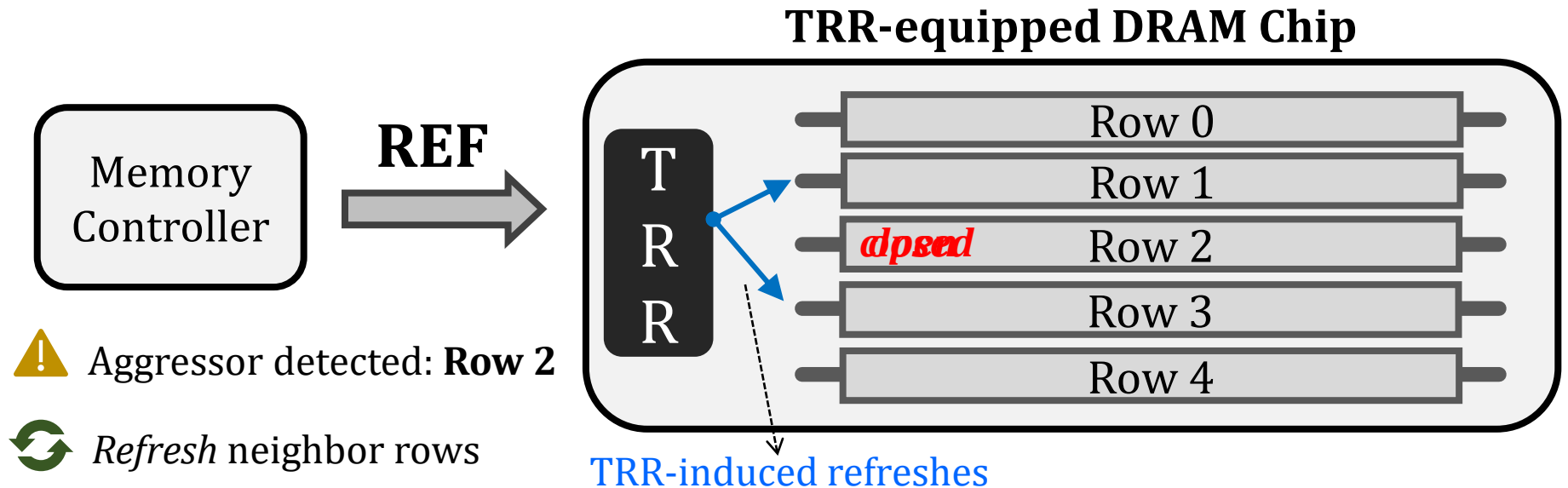


Repeatedly **opening** (activating) and **closing** (precharging) a DRAM row causes **RowHammer bit flips** in nearby cells

Target Row Refresh (TRR)

DRAM vendors equip their DRAM chips with a *proprietary* mitigation mechanisms known as **Target Row Refresh (TRR)**

Key Idea: TRR refreshes nearby rows upon detecting an aggressor row



The Problem with TRR

TRR is **obscure, undocumented, and proprietary**

We **cannot** easily study the *security properties* of TRR

Goal

Study in-DRAM TRR mechanisms to

- 1 **understand** how they operate
- 2 **assess** their security
- 3 **secure** DRAM completely against RowHammer

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Overview of U-TRR

U-TRR: A new methodology to *uncover* the inner workings of TRR

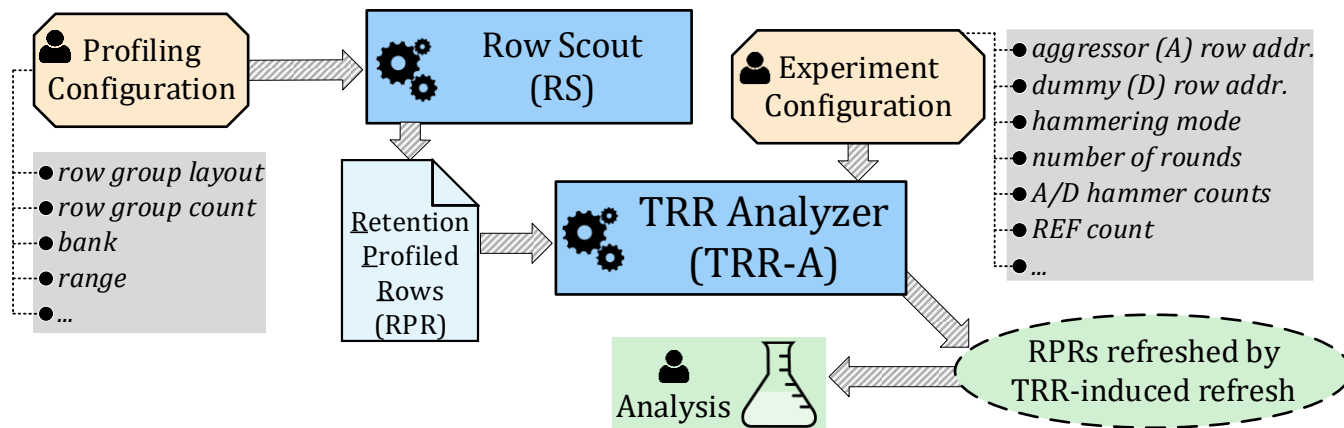
Key idea: Use **data retention failures** as a side channel to **detect when a row is refreshed** by TRR

High-Level U-TRR Operation

U-TRR has two main components:
Row Scout (RS) and **TRR Analyzer (TRR-A)**

Row Scout: finds a **set of DRAM rows** that meet certain requirements as needed by TRR-A and **identifies the data retention times** of these rows

TRR Analyzer: uses RS-provided rows to **distinguish between TRR-induced and regular refreshes**, and thus builds an understanding of the underlying TRR mechanism

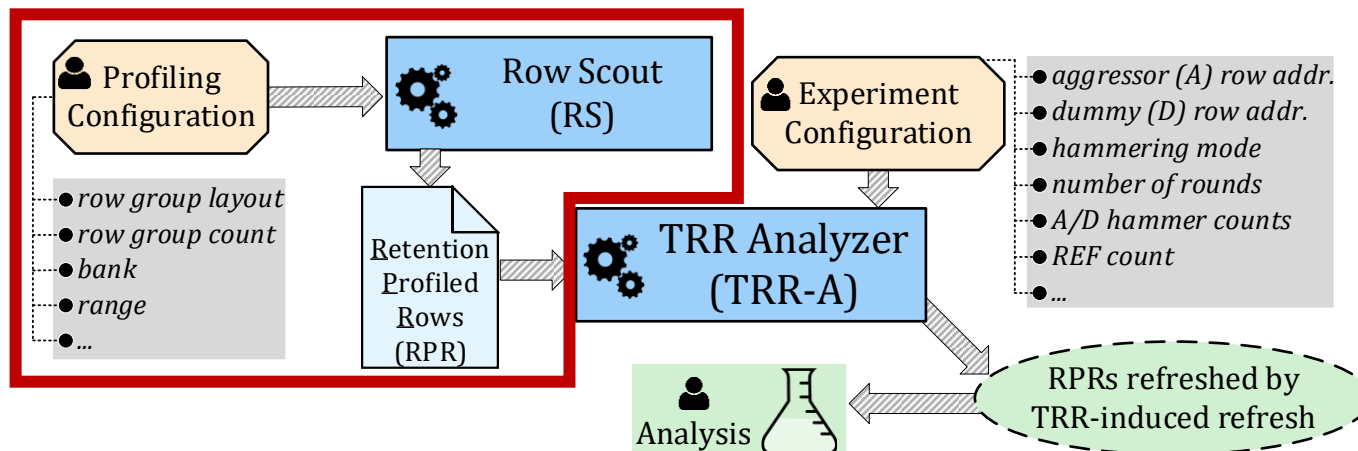


Row Scout (RS)

Goal: Identify a list of *useful* DRAM rows and their *retention times*

Row Scout **must** find:

- ✓ Rows with **consistent*** retention times
 - To correctly infer **whether a row has been refreshed**
- ✓ **Multiple rows** that are located at *certain configurable distances* and have the *same retention time (i.e., Row Group)*
 - To observe **whether TRR can refresh multiple rows** at the same time

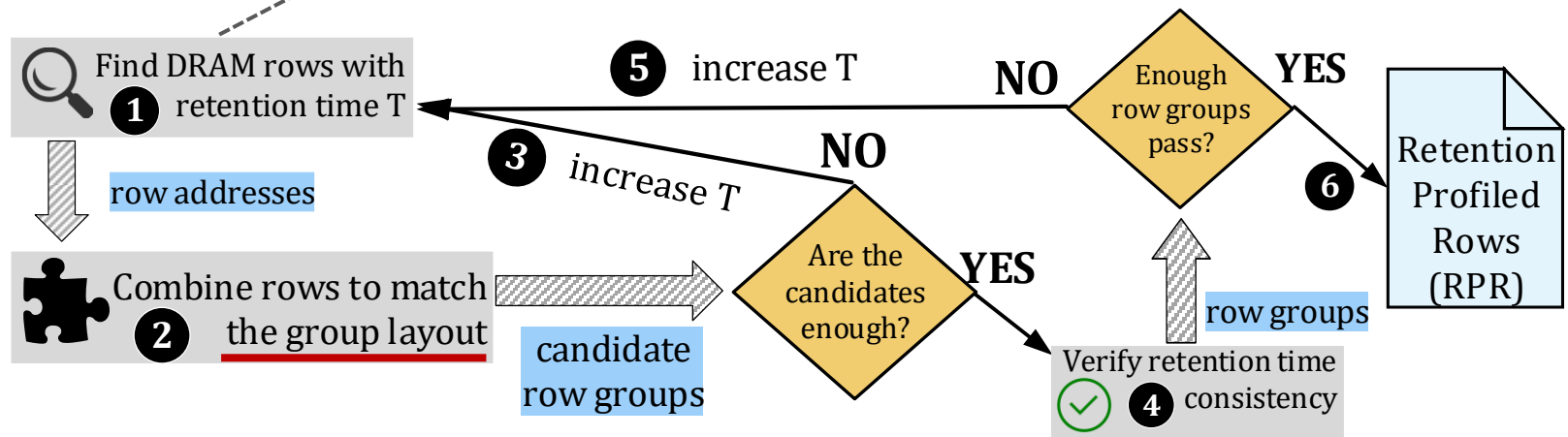


* The retention time of a DRAM row may change over time due to Variable Retention Time (VRT) effects

Row Scout (RS) Operation

Profiling the **retention time** of a DRAM row:

- 1) write data
- 2) wait for T
- 3) check for retention bit flips



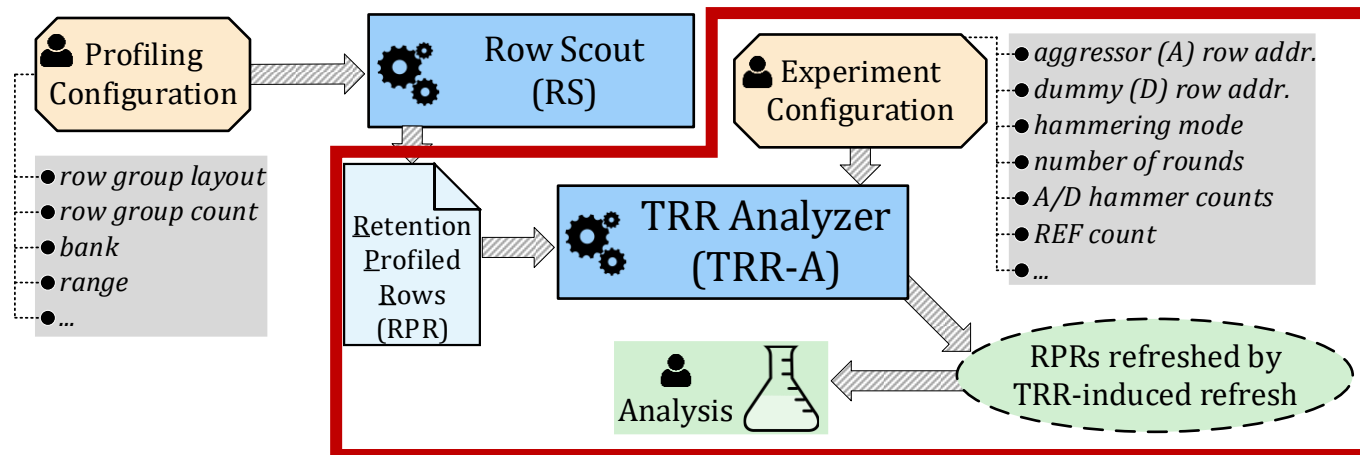
Row Group: V □ V □ V

TRR Analyzer (TRR-A)

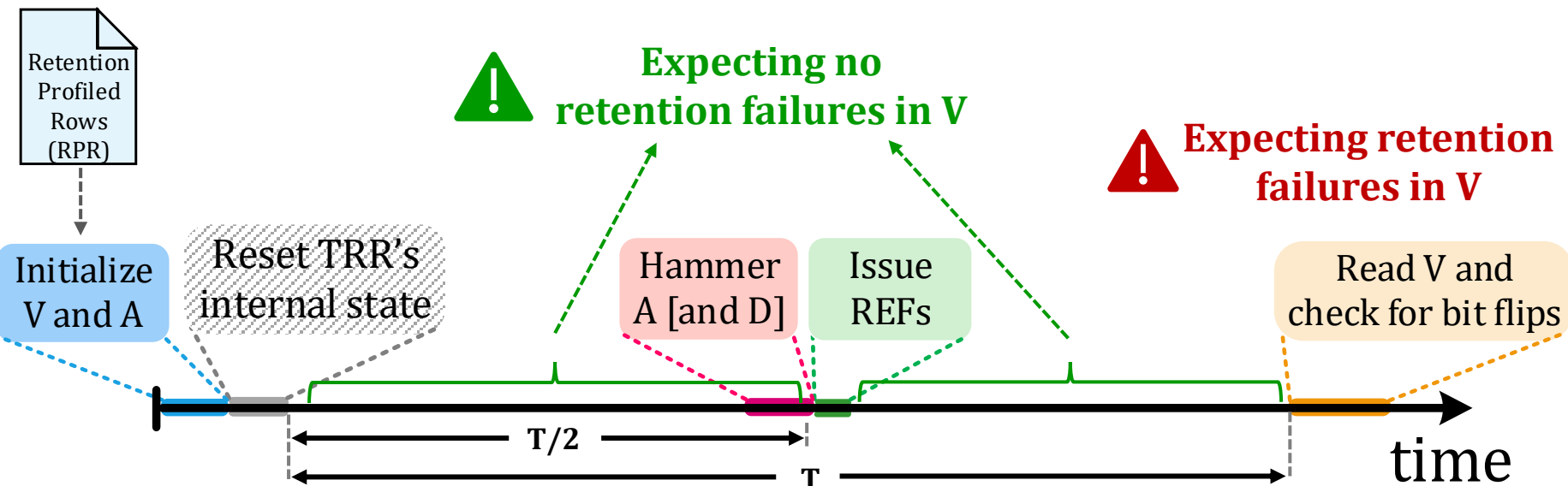
Goal: Use RS-provided rows to determine when TRR refreshes a victim row

High-level Operation:

- 1) Run a certain **DRAM access pattern** (i.e., RowHammer attack)
- 2) **Monitor** retention failures in RS-provided rows to determine **when TRR refreshes any of these rows**
- 3) Develop an understanding of the **underlying TRR operation**



TRR Analyzer (TRR-A) Operation



Row Group: **V** **A** **V** **A** **V**

- i** V: victim (RS-provided) rows
- A: aggressor rows
- D: dummy rows

- Experiment Configuration
- aggressor (A) row addr.
 - dummy (D) row count
 - hammering mode
 - number of rounds
 - A/D hammer counts
 - REF count

TRR-A helps to understand how TRR operates based on when Retention Profiled Rows are refreshed by TRR

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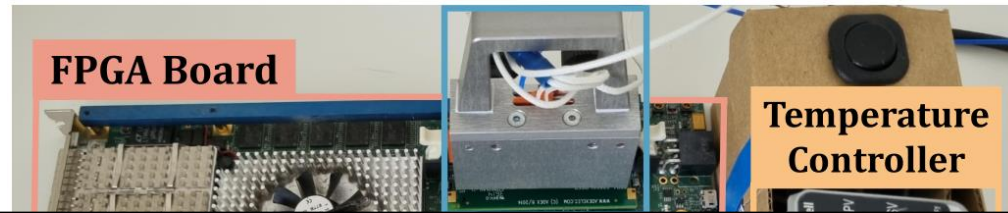
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DRAM Testing Infrastructure

We implement **U-TRR** using
FPGA-based *SoftMC* [Hassan+, HPCA'17]
modified to support DDR4 DRAM



Module	Date (yy-ww)	Chip Density (Gbit)	Organization			HC _{first} [†]	Our Key TRR Observations and Results							
			Ranks	Banks	Pins		Version	Aggressor Detection	Aggressor Capacity	Per-Bank TRR	TRR-to-REF Ratio	Neighbors Refreshed	% Vulnerable DRAM Rows [†]	Max. Bit Flips per Row per Hammer [†]
A0	19-50	8	1	16	8	16K	A _{TRR1}	Counter-based	16	✓	1/9	4	73.3%	1.16
A1-5	19-36	8	1	8	16	13K-15K	A _{TRR1}	Counter-based	16	✓	1/9	4	99.2% - 99.4%	2.32 - 4.73
A6-7	19-45	8	1	8	16	13K-15K	A _{TRR1}	Counter-based	16	✓	1/9	4	99.3% - 99.4%	2.12 - 3.86
A8-9	20-07	8	1	16	8	12K-14K	A _{TRR1}	Counter-based	16	✓	1/9	4	74.6% - 75.0%	1.96 - 2.96
A10-12	19-51	8	1	16	8	12K-13K	A _{TRR1}	Counter-based	16	✓	1/9	4	74.6% - 75.0%	1.48 - 2.86
A13-14	20-31	8	1	8	16	11K-14K	A _{TRR2}	Counter-based	16	✓	1/9	2	94.3% - 98.6%	1.53 - 2.78
B0	18-22	4	1	16	8	44K	B _{TRR1}	Sampling-based	1	✗	1/4	2	99.9%	2.13
B1-4	20-17	4	1	16	8	159K-192K	B _{TRR1}	Sampling-based	1	✗	1/4	2	23.3% - 51.2%	0.06 - 0.11
B5-6	16-48	4	1	16	8	44K-50K	B _{TRR1}	Sampling-based	1	✗	1/4	2	99.9%	1.85 - 2.03
B7	19-06	8	2	16	8	20K	B _{TRR1}	Sampling-based	1	✗	1/4	2	99.9%	31.14
B8	18-03	4	1	16	8	43K	B _{TRR1}	Sampling-based	1	✗	1/4	2	99.9%	2.57
B9-12	19-48	8	1	16	8	42K-65K	B _{TRR2}	Sampling-based	1	✗	1/9	2	36.3% - 38.9%	16.83 - 24.26
B13-14	20-08	4	1	16	8	11K-14K	B _{TRR3}	Sampling-based	1	✓	1/2	4	99.9%	16.20 - 18.12
C0-3	16-48	4	1	16	x8	137K-194K	C _{TRR1}	Mix	Unknown	✓	1/17	2	1.0% - 23.2%	0.05 - 0.15
C4-6	17-12	8	1	16	x8	130K-150K	C _{TRR1}	Mix	Unknown	✓	1/17	2	7.8% - 12.0%	0.06 - 0.08
C7-8	20-31	8	1	8	x16	40K-44K	C _{TRR1}	Mix	Unknown	✓	1/17	2	39.8% - 41.8%	9.66 - 14.56
C9-11	20-31	8	1	8	x16	42K-53K	C _{TRR2}	Mix	Unknown	✓	1/9	2	99.7%	9.30 - 32.04
C12-14	20-46	16	1	8	x16	6K-7K	C _{TRR3}	Mix	Unknown	✓	1/8	2	99.9%	4.91 - 12.64

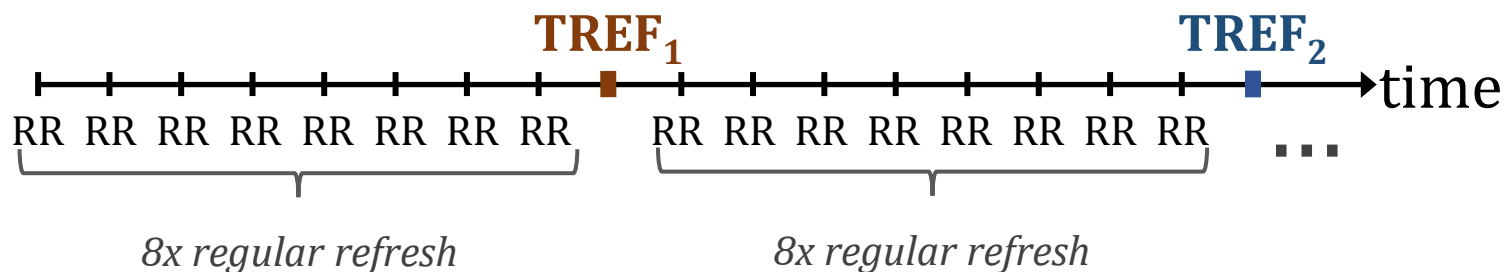
 **Table 1** in our paper provides more information about the analyzed modules

 **15x Vendor C DDR4 modules**

Key Observations: Vendor A

Refresh Types:

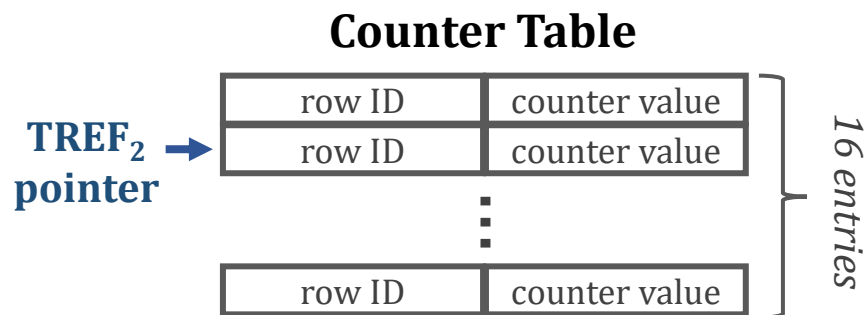
- Regular Refresh (RR)
- TRR-capable Refresh (**TREF₁** and **TREF₂**)



Observation: TRR tracks potentially aggressor rows using a **Counter Table**

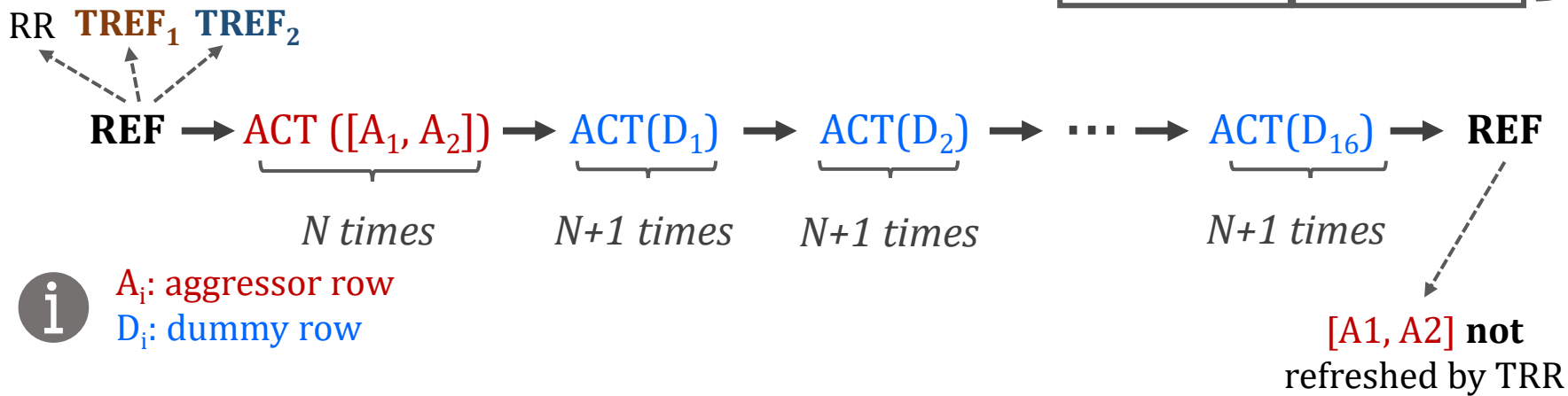
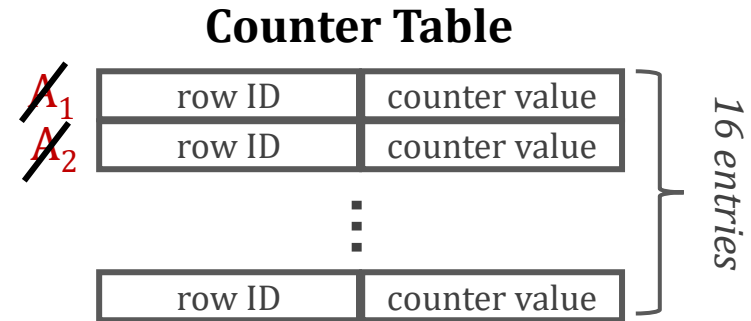
TREF₁: Refreshes the victims of **row ID** with the **largest counter value**

TREF₂: Refreshes the victims of **row ID** that **TREF₂ pointer** refers to



Circumventing Vendor A's TRR

Approach: Ensure an **aggressor** row is **discarded** from the *Counter Table* prior to a REF command



A_i: aggressor row
D_i: dummy row



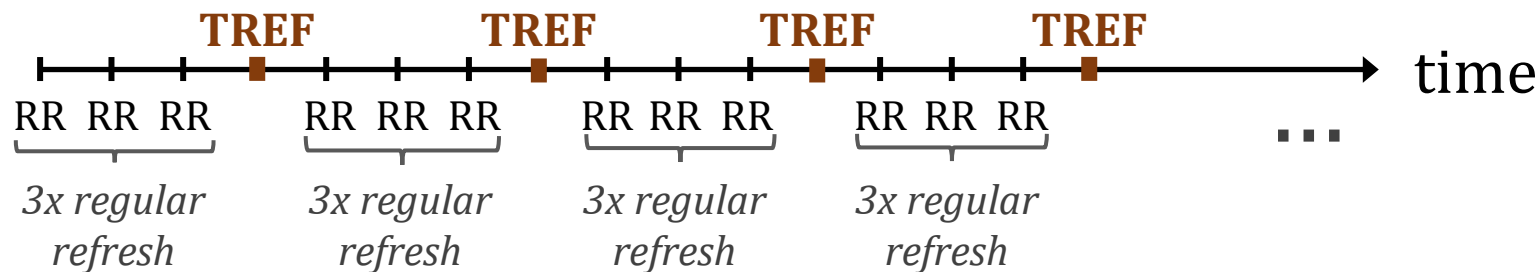
This RowHammer access pattern requires **synchronizing accesses** with REF commands

Circumventing Vendor A's TRR by **discarding** the actual **aggressor rows** from the Counter Table

Key Observations: Vendor B

Refresh Types:

- Regular Refresh (RR)
- TRR-capable Refresh (**TREF**)



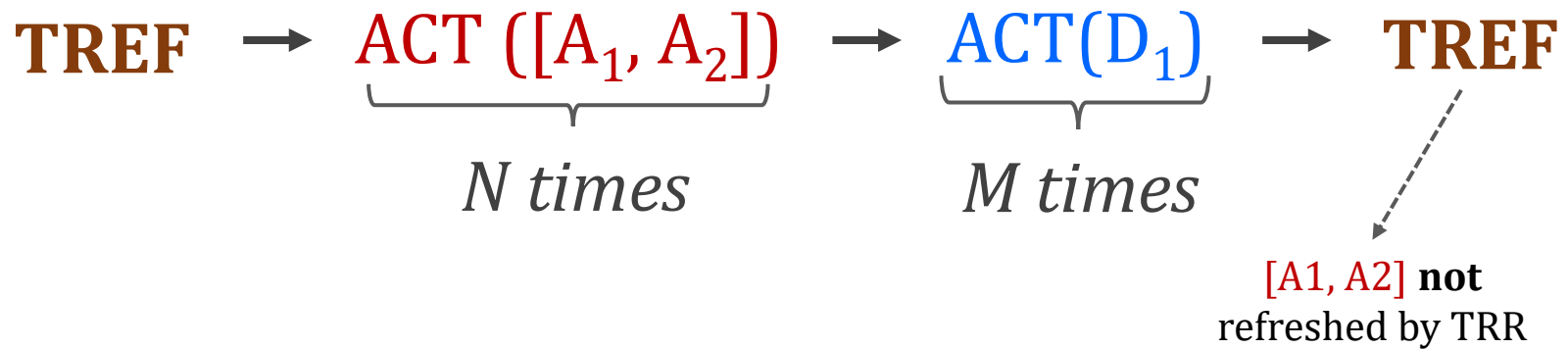
Observation 1: TRR *probabilistically* samples the address of an activated row

Observation 2: A newly-sampled row overwrites the previously-sampled one

TREF: Refreshes the victims of the **last sampled row**

Circumventing Vendor B's TRR

Approach: Maximize the **dummy** row hammers **after** hammering the **aggressor** rows and **before** the next **TREF**

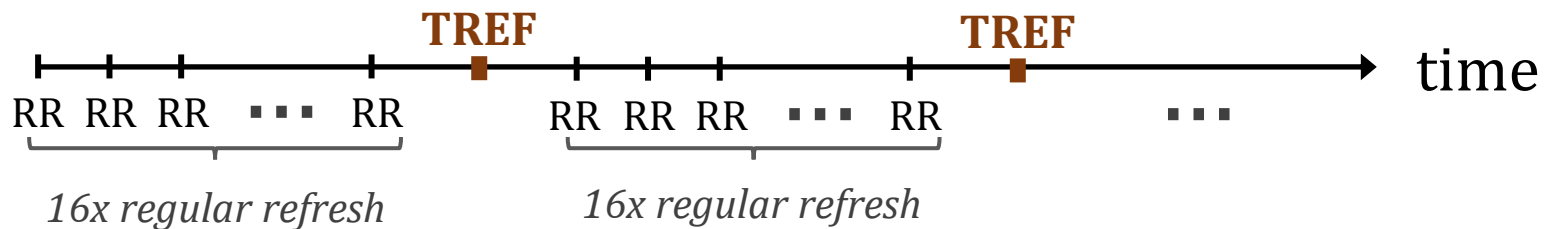


Circumventing Vendor B's TRR by making it **replace** a **sampled aggressor row** by **sampling a dummy row**

Key Observations: Vendor C

Refresh Types:

- Regular Refresh (RR)
- TRR-capable Refresh (**TREF**)



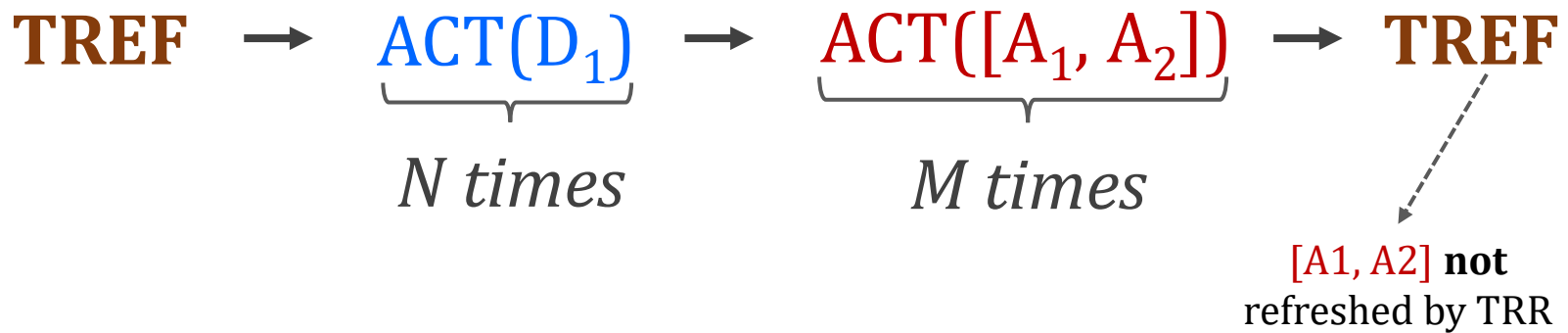
Observation 1: TRR detects an aggressor row only among the first 2K ACT commands issued after a **TREF**

Observation 2: Rows activated earlier within the 2K ACT commands are more likely to be detected by TRR

TREF: Detects an aggressor row only among the first 2K ACT commands while favoring the earlier activations more

Circumventing Vendor C's TRR

Approach: Hammer **dummy** rows before **aggressor** rows to maximize the probability of TRR detecting a **dummy** row



Circumventing Vendor C's TRR by **first hammering dummy rows** to make **aggressor rows** **less likely** to be detected

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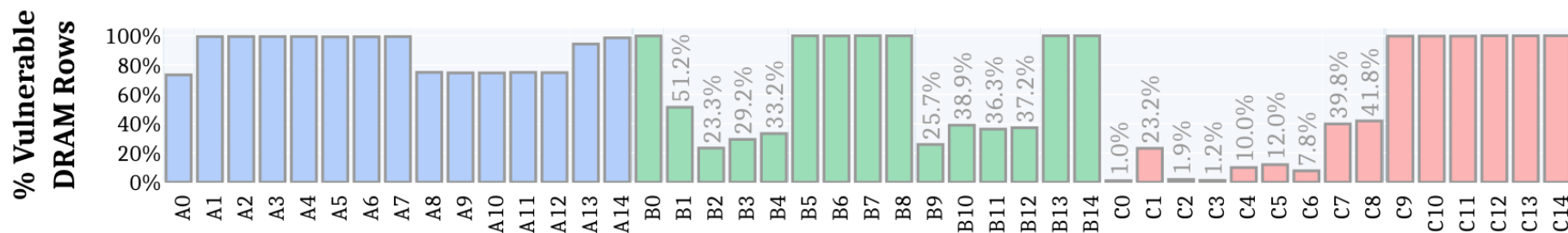
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Bypassing TRR with New RowHammer Access Patterns

We craft **new RowHammer access patterns** that **circumvent TRR** of three major DRAM vendors

On the **45** DDR4 modules we test, the **new access patterns** cause **a large number of RowHammer bit flips**

Effect on Individual Rows



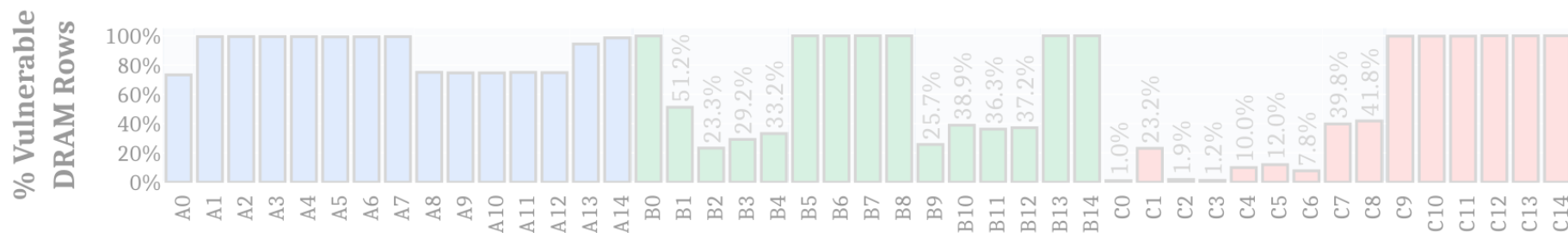
All 45 modules we tested are **vulnerable** to our new RowHammer access patterns

Our RowHammer access patterns cause bit flips in more than **99.9%** of the rows

Why are some modules less vulnerable?

- 1) Fundamentally less vulnerable to RowHammer
- 2) Different TRR mechanisms
- 3) Unique row organization

Effect on Individual Rows



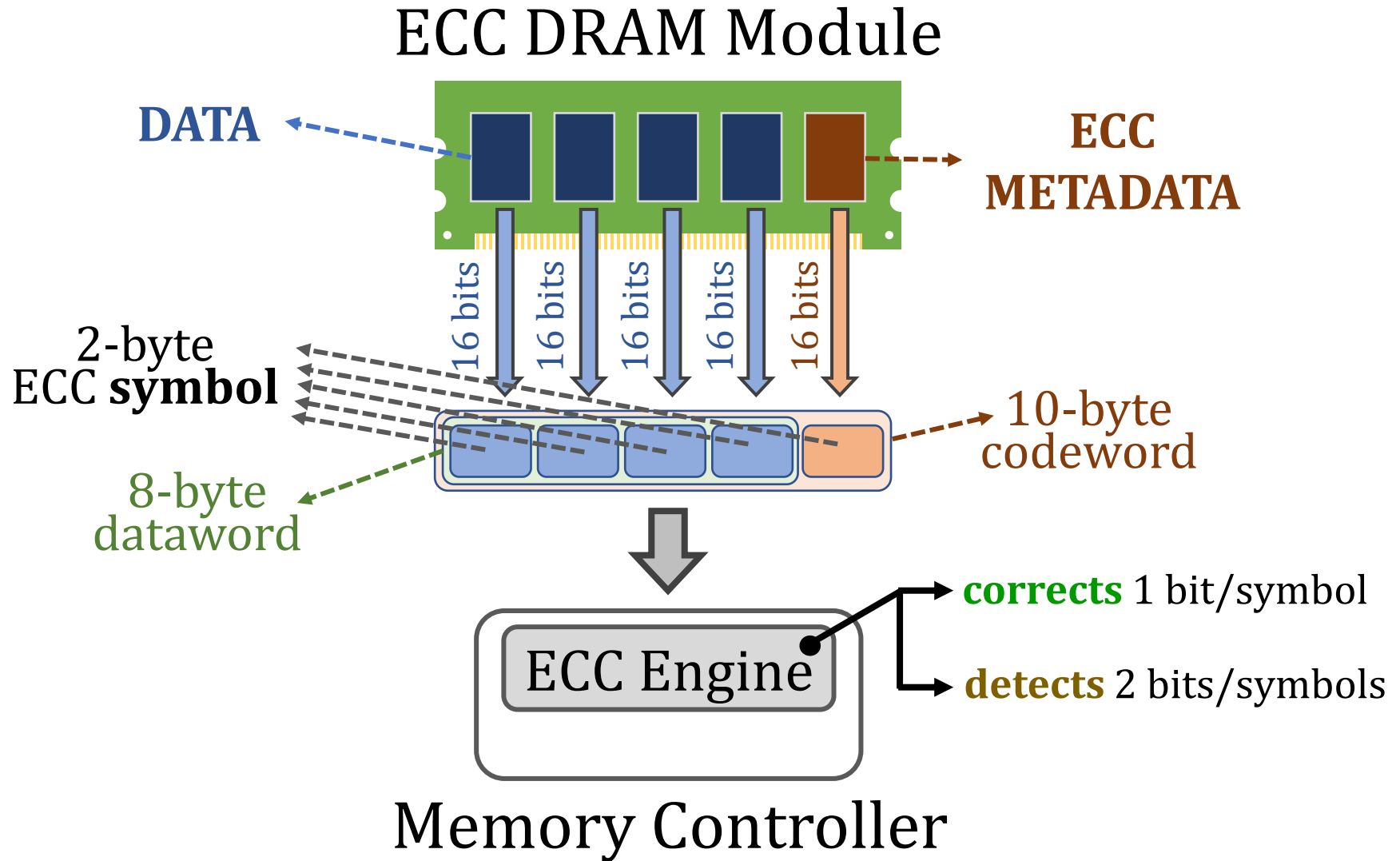
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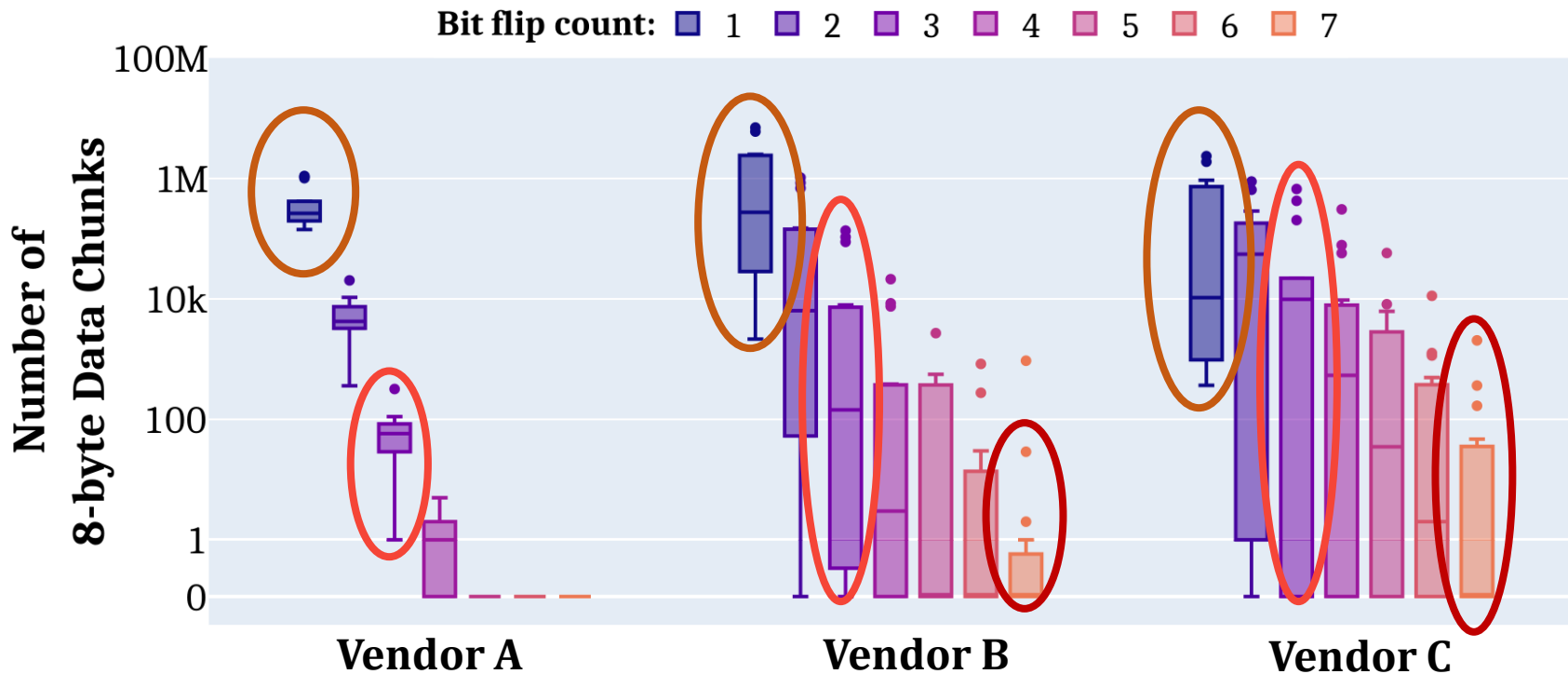
Our access patterns successfully circumvent the TRR implementations of all three major DRAM vendors

3) Unique row organization

Can ECC Protect Against Our Access Patterns?



Bypassing ECC with New RowHammer Patterns



Modules from all three vendors have many **8-byte data chunks** with **3 and more (up to 7) RowHammer bit flips**

Conventional DRAM ECC **cannot protect** against our **new RowHammer access patterns**

Other Observations and Results in the Paper

- More observations on the TRRs of the three vendors
- Detailed description of the crafted access patterns
- Hammers per aggressor row sensitivity analysis
- Observations and results for individual modules
- ...

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A13-14	20-31	8	1	8	16	11K-14K	<i>ATRR2</i>	Counter-based	16	✓	1/9	2	94.3% - 98.6%	1.53 - 2.78
B0	18-22	4	1	16	8	44K	<i>BTRR1</i>	Sampling-based	1	✗	1/4	2	99.9%	2.13
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C4-6	17-12	8	1	16	x8	130K-150K	<i>CTRR1</i>	Mix	Unknown	✓	1/17	2	7.8% - 12.0%	0.06 - 0.08
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C9-11	20-31	8	1	8	x16	42K-53K	<i>CTRR2</i>	Mix	Unknown	✓	1/9	2	99.7%	9.30 - 32.04
C12-14	20-46	16	1	8	x16	6K-7K	<i>CTRR3</i>	Mix	Unknown	✓	1/8	2	99.9%	4.91 - 12.64

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experience **at least one RowHammer bit flip**

Up to 7 RowHammer **bit flips** in
an 8-byte dataword, **making ECC ineffective**

TRR **does not provide security** against RowHammer

U-TRR can **facilitate** the development of **new RowHammer attacks**
and **more secure RowHammer protection** mechanisms

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